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	<b>Filing Date</b>	
	<b>First Named Inventor</b>	MARINISSEN, ERIK J.
	<b>Group Art Unit</b>	
	<b>Examiner Name</b>	
	<b>Atty. Docket Number</b>	<b>NL040065US1</b>

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
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FOREIGN PATENT DOCUMENTS						
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NON-PATENT LITERATURE DOCUMENTS			
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	1	WAAYERS T ED - INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS: "AN IMPROVED TEST CONTROL ARCHITECTURE AND TEST CONTROL EXPANSION FOR CORE-BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2003. (ITC); CHARLOTTE NC. SEPT. 30, OCT. 2, 2003; INTERNATIONAL TEST CONF. N.Y.: IEEE US VOL. 1, 30 SEPT 2003; PP 1145-1154	
	2	ZORIAN Y ET AL: "TESTING EMBEDDED-CORE BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 1998 (IEEE CAT. NO. 98CH36270) INT. TEST CONF. WASHINGTON DC USA; ONLINE 23 OCT. 1998 (1998-10-23) PP 130-143.	

<b>Examiner Signature</b>		<b>Date Considered</b>	
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<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.